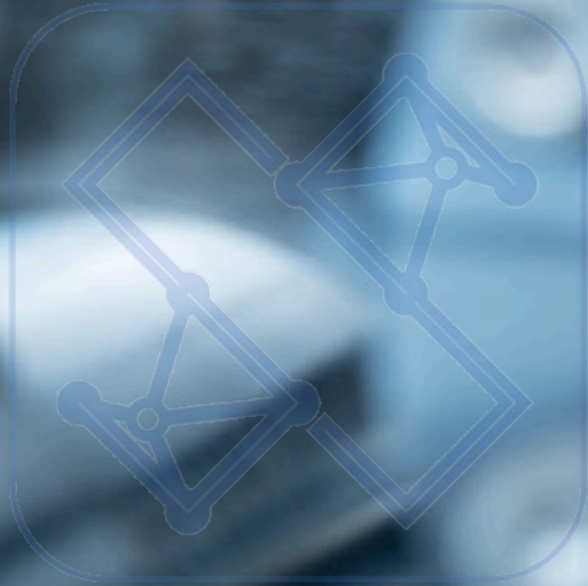


Lecture 4:

Microscopic Picture of Ion Transport



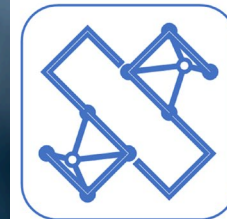
SSI Lab

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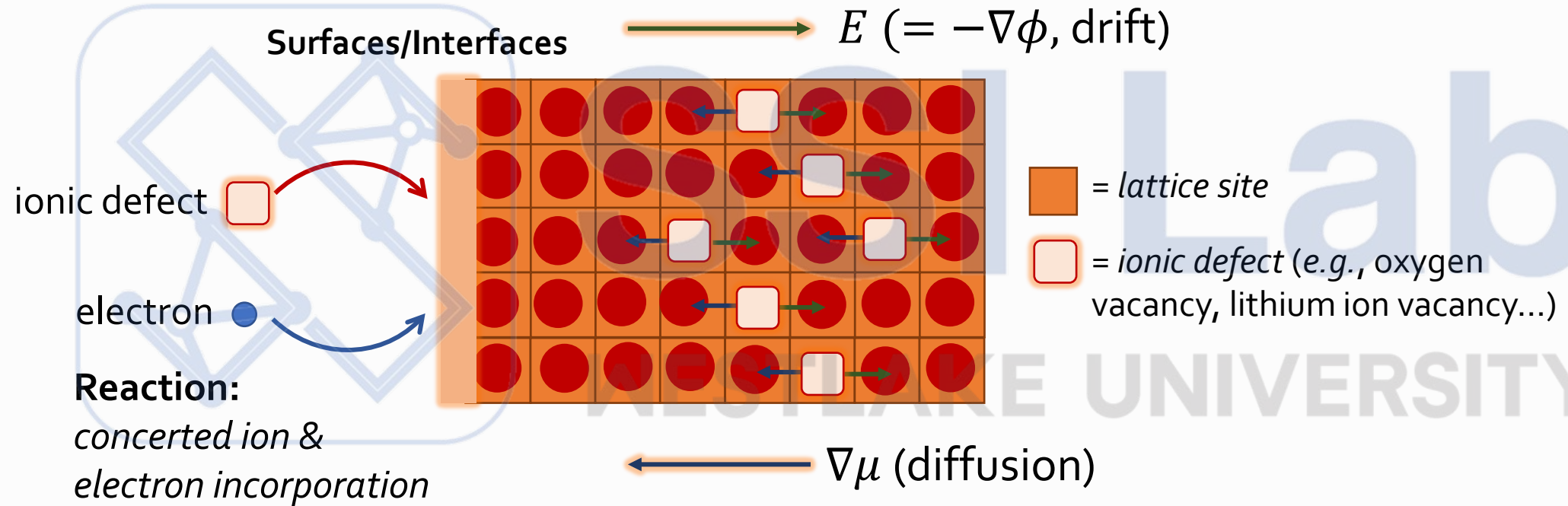
Prof. Qiyang Lu

Solid State Ionics (SSI) Laboratory

School of Engineering, Westlake University



Diffusion and reactions in solid states w/ the picture of ionic defects



Ion motion: drift + diffusion
(similar to electrons/holes in semiconductor physics)

Things we will discuss in this lecture

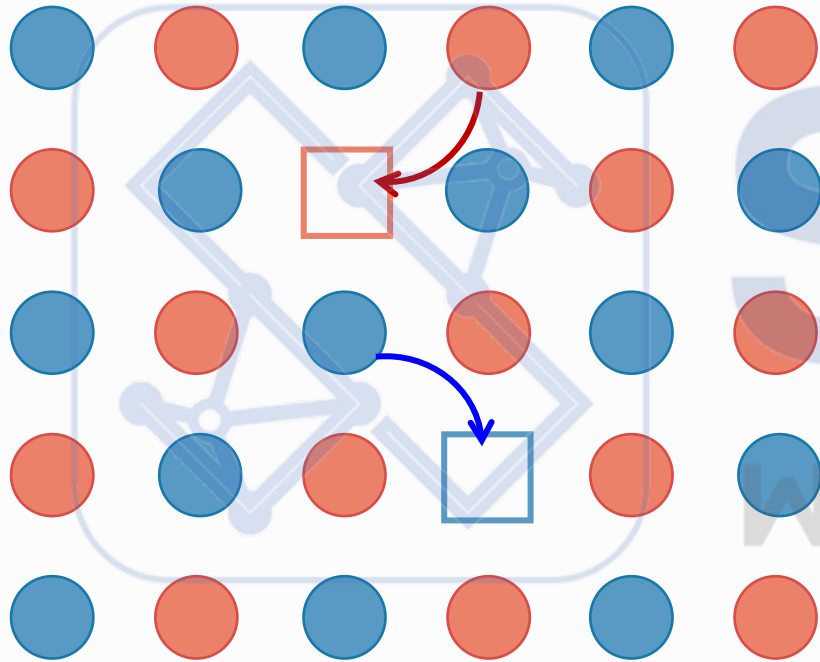
Microscopic picture of ion transport:

- What are the microscopic mechanisms for ionic migration based on the type of ionic defects?
- How to derive the Fick's law from the microscopic picture of ion migration?
- How to reach the Nernst-Einstein relation (correlating the diffusivity and the mobility) from the microscopic picture of ion transport?

Goal of this lecture: you should be able to answer the questions above by the end of this lecture :)

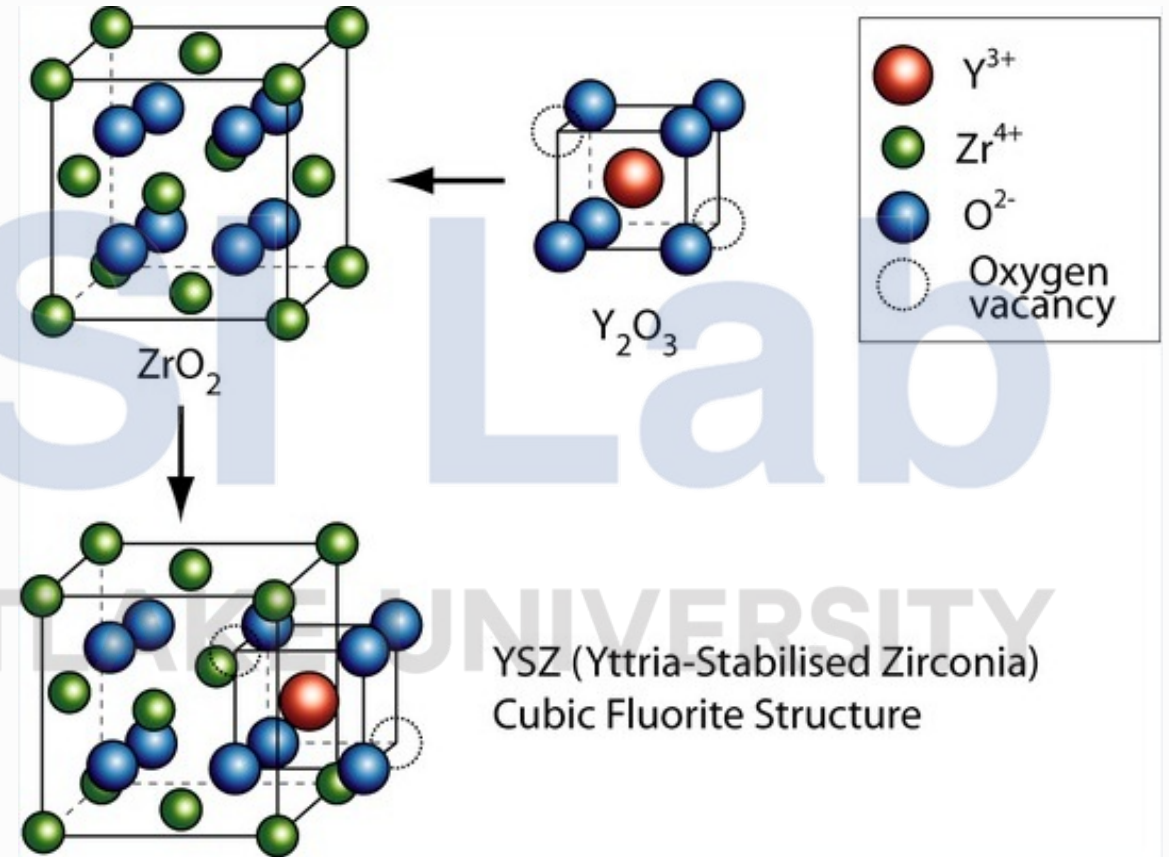
Mechanisms of ionic defect migration in crystals

Vacancy mechanism



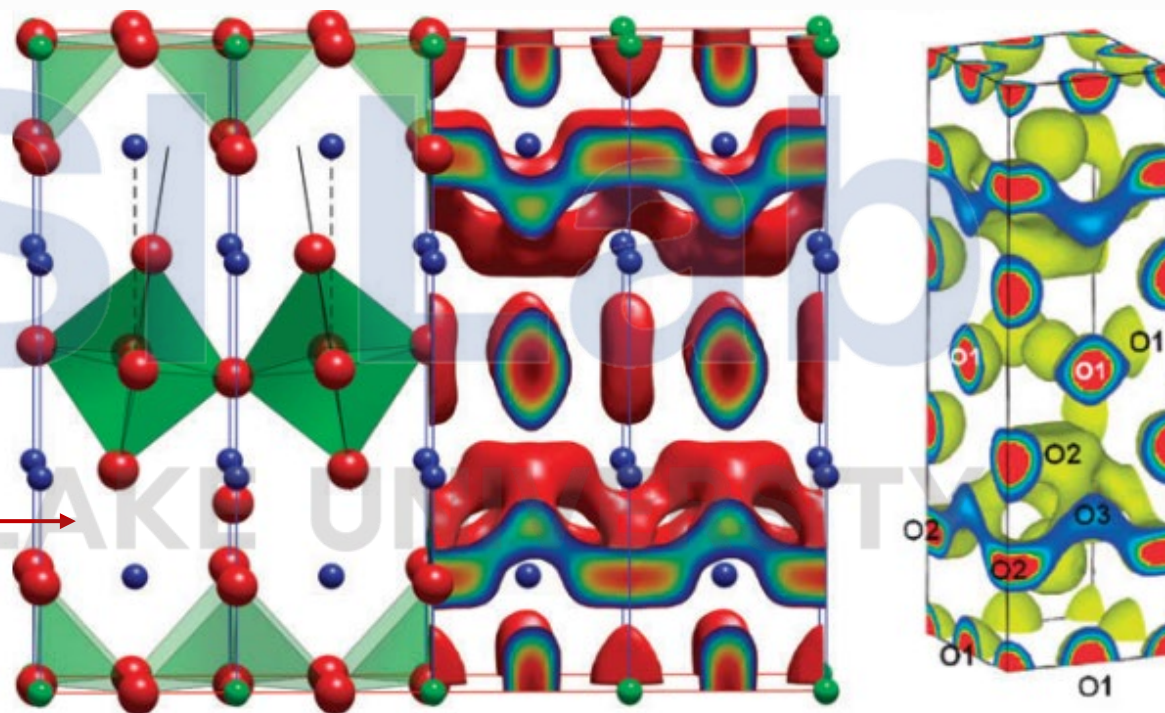
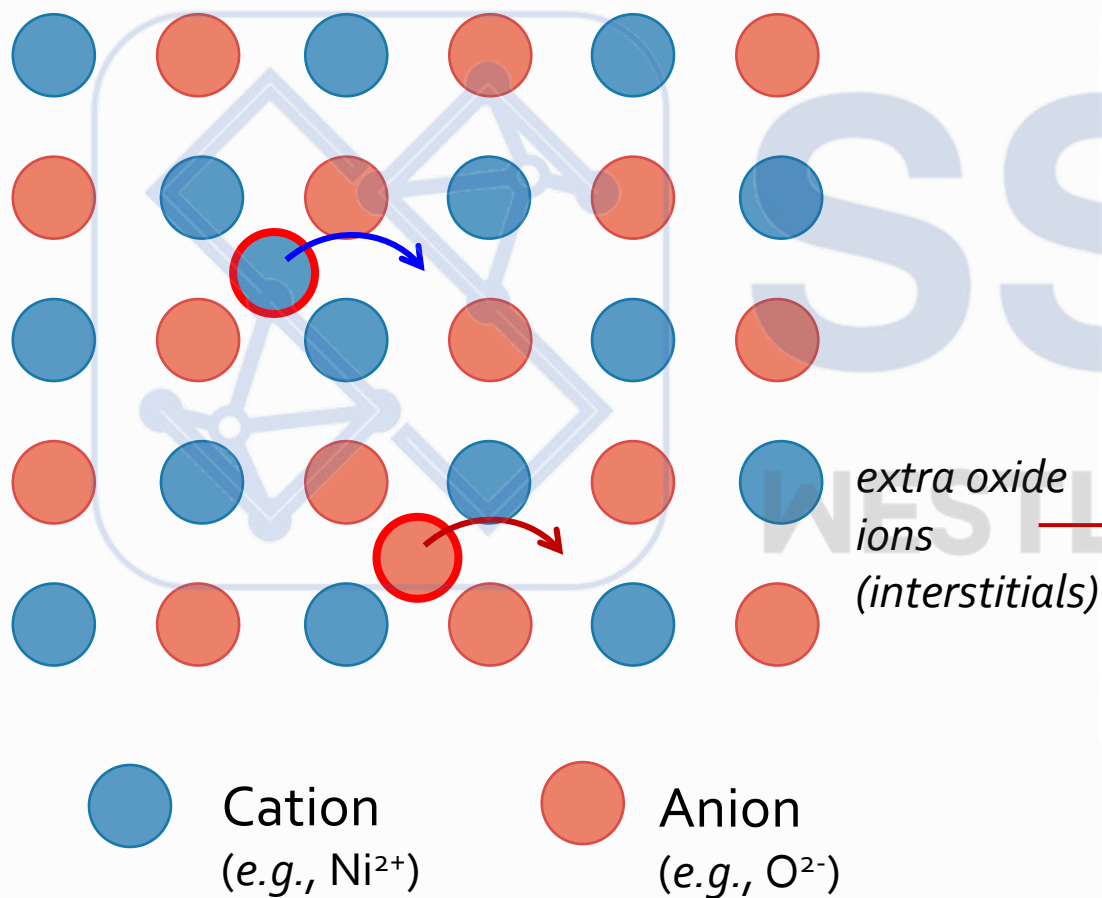
● Cation
(e.g., Ni^{2+})

● Anion
(e.g., O^{2-})



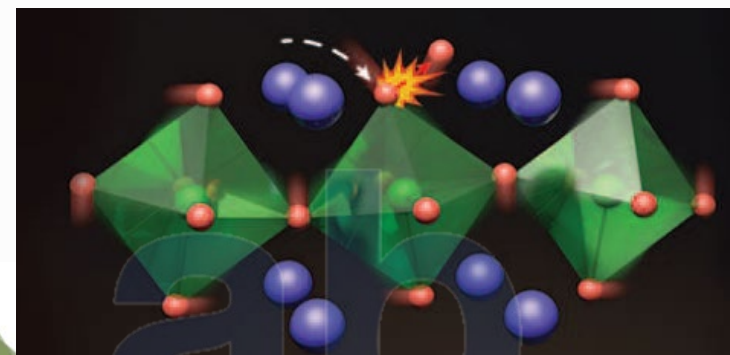
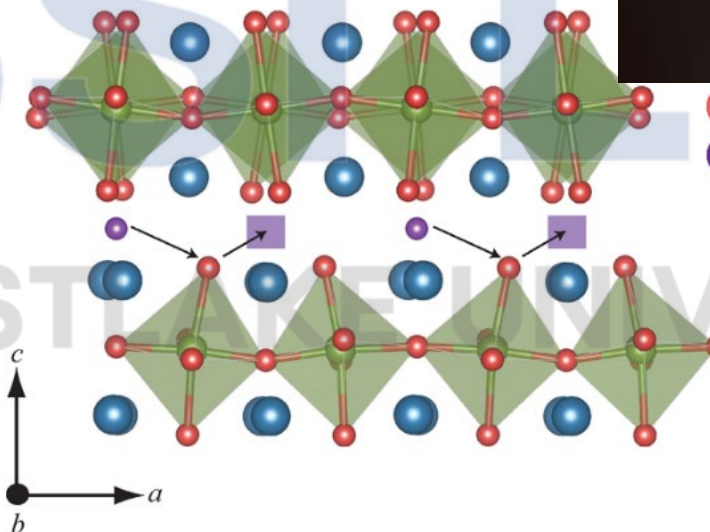
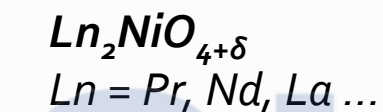
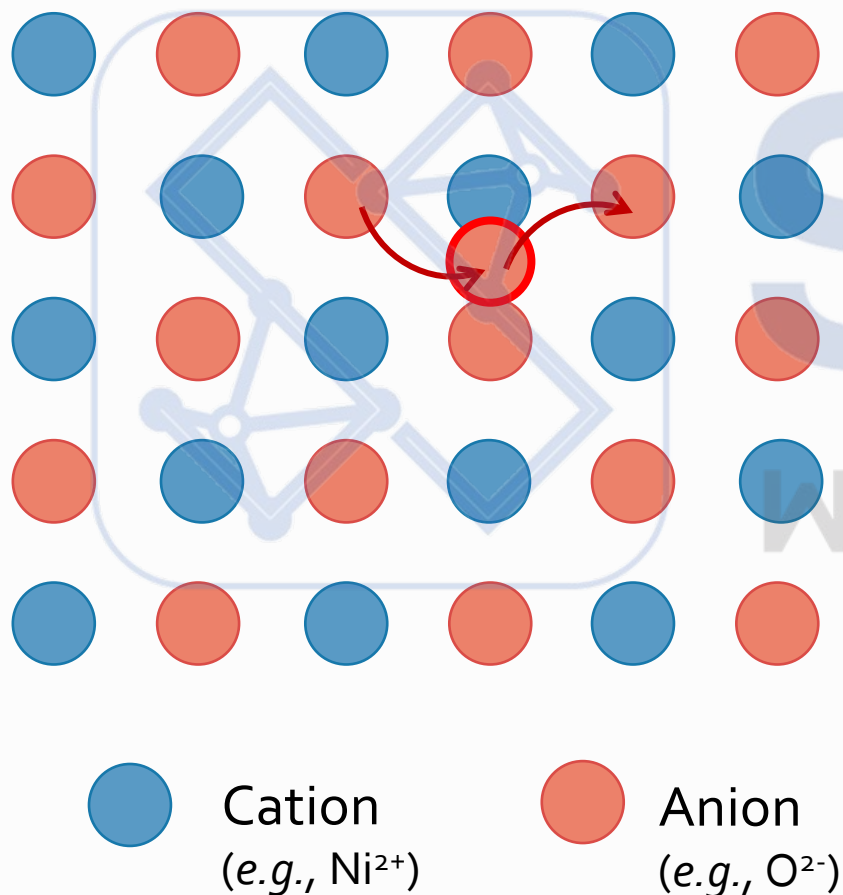
Ionic defects are needed for ion migration in crystals.

Interstitial mechanism



Parfitt et al., *PCCP*, 2010

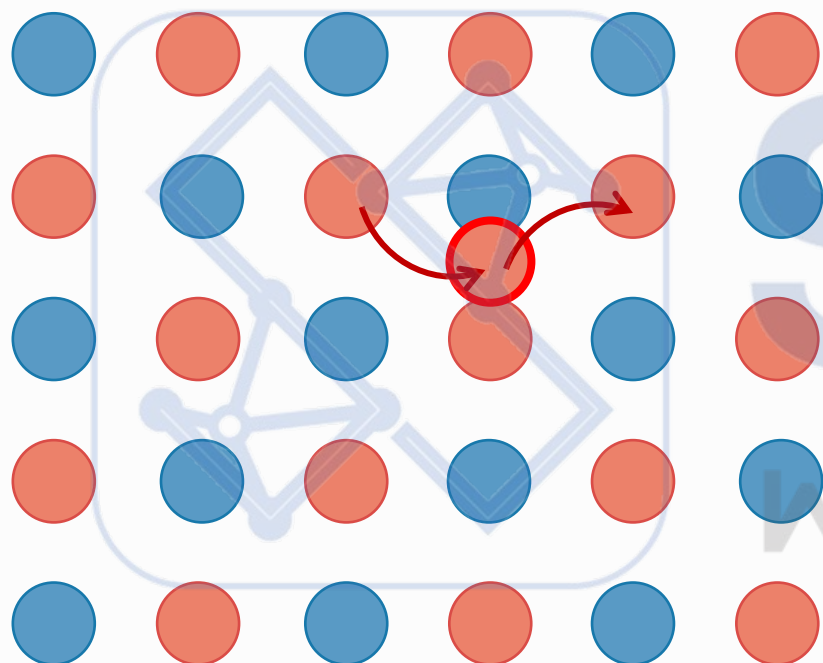
Interstitialcy mechanism



Oxide ion transport
 through "**concerted
 motion**" of multiple
 ions/ionic defects.

Li & Benedek, *Chem. Mater.*, 2015

Interstitialcy mechanism

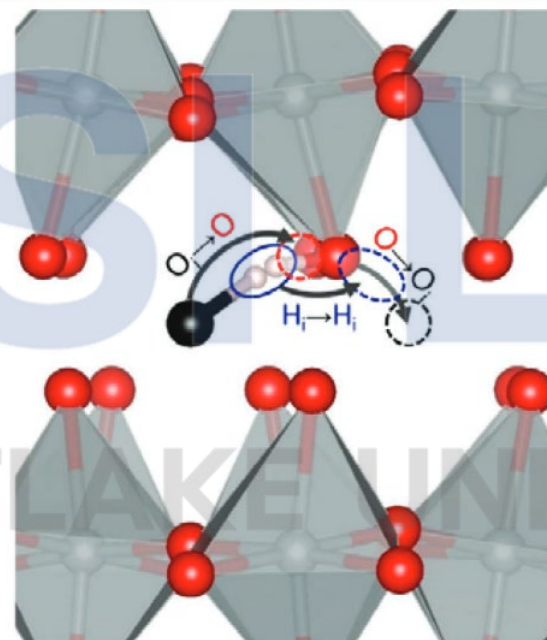


Cation
(e.g., Ni^{2+})



Anion
(e.g., O^{2-})

$\text{La}_2\text{NiO}_{4+\delta}$ w/ *protons*



Protons forms “-OH” group with oxygen interstitials.

Cooperative proton-oxide ion transport via interstitialcy mechanism.

Protons on lattice oxygen site

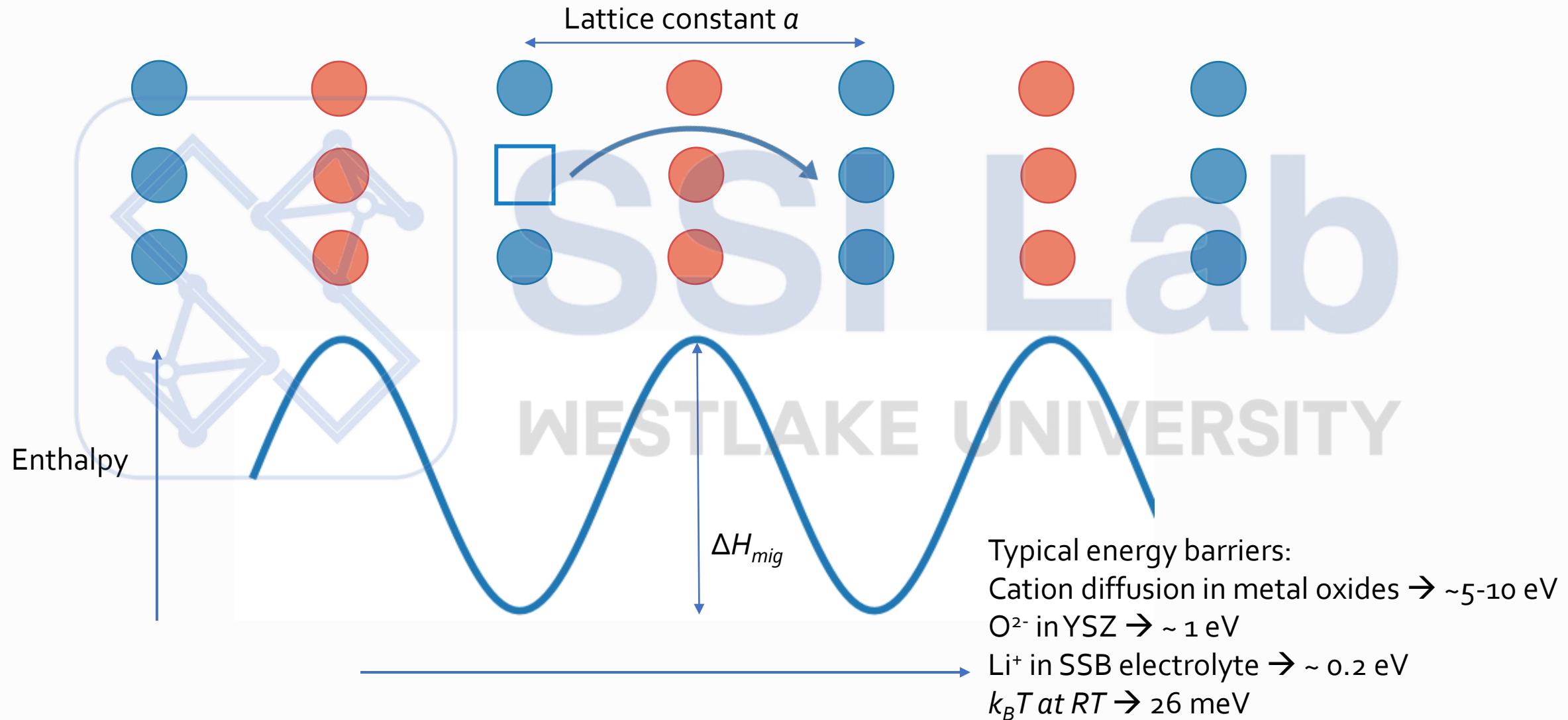
$\rightarrow \text{OH}_0$

Protons on oxygen interstitial

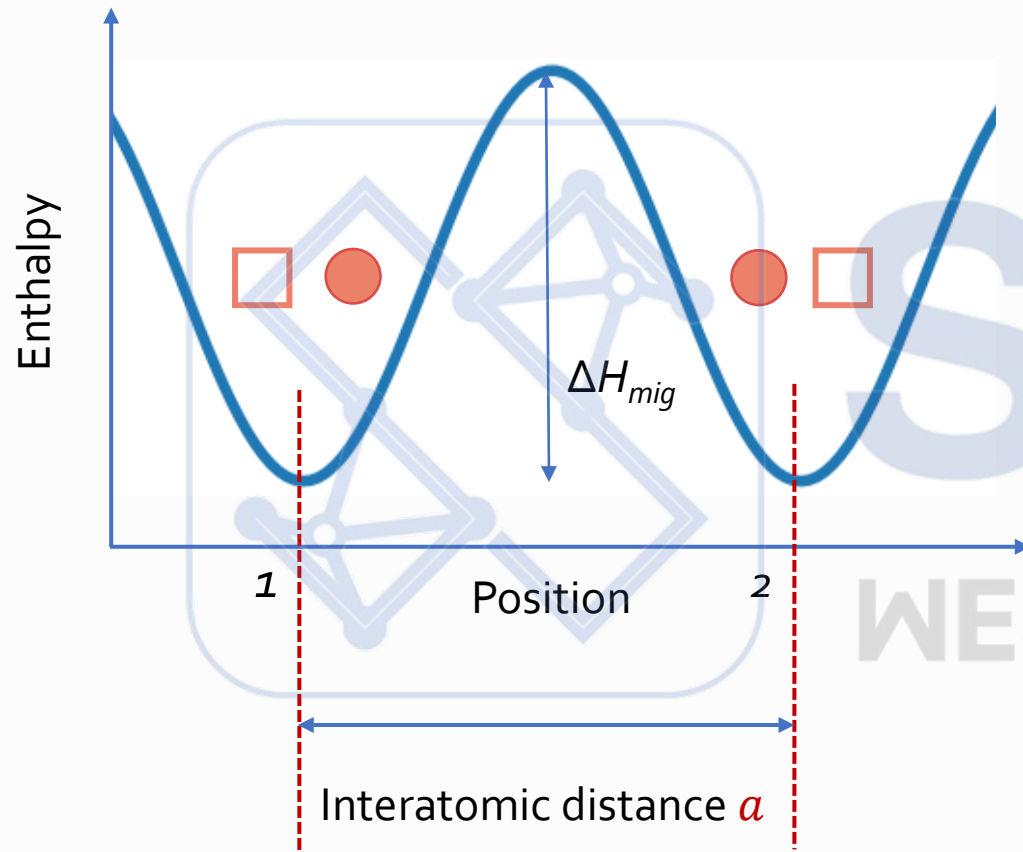
$\rightarrow \text{OH}'_i$

Zhong, Norby, Han et al., *Adv. Energy Mater.*, 2022

Ion migration and energy barriers



Hop frequency, attempt frequency and mean free time



$$\Gamma = \nu \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

Hop frequency

Attempt frequency

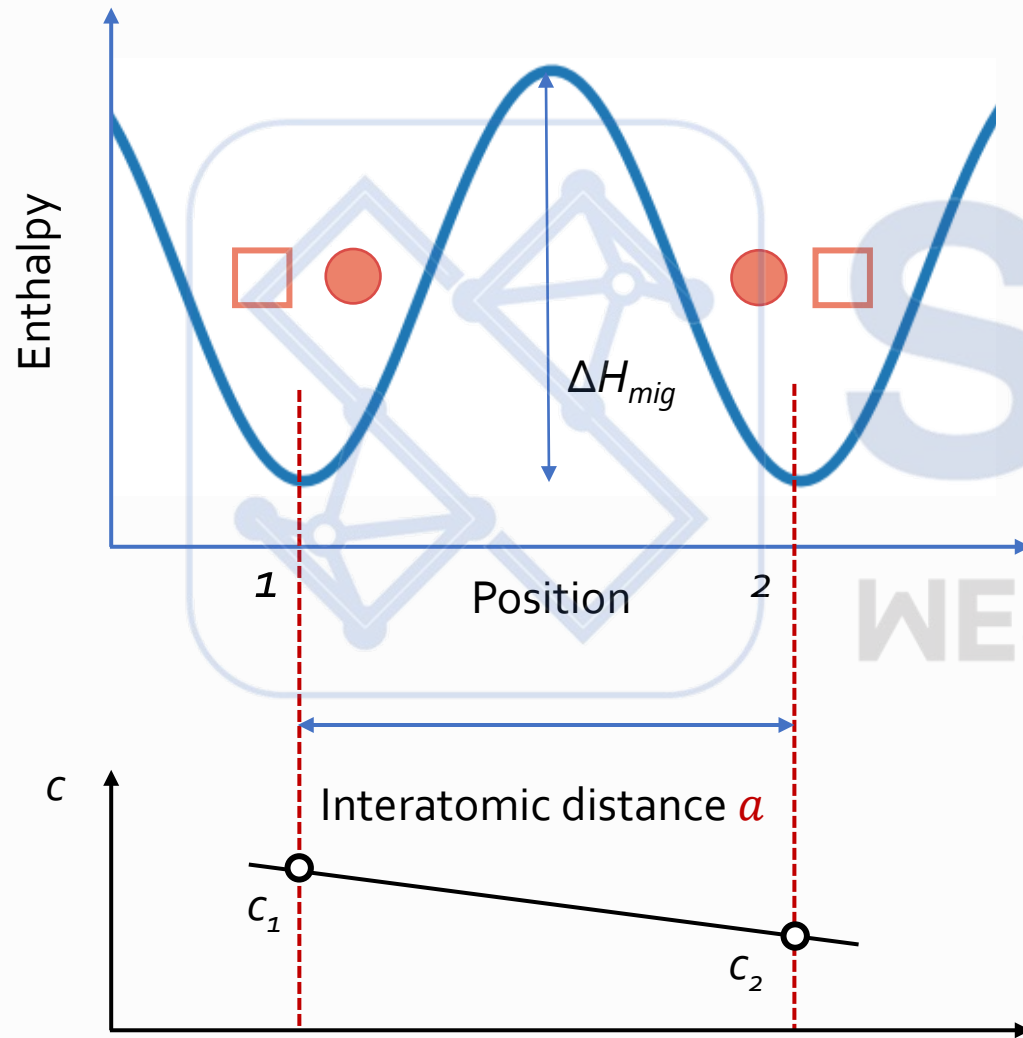
"success rate"
(Boltzmann probability)

Hop frequency
(unit: s^{-1})

$$\Gamma = \frac{1}{\tau}$$

"Mean free time"
(unit: s)

Microscopic origin of Fick's law



$$J = J_{1 \rightarrow 2} - J_{2 \rightarrow 1}$$

$$J_{1 \rightarrow 2} = \frac{\frac{1}{2}N_1\Gamma}{A} = \frac{\frac{1}{2}c_1aA\Gamma}{A} = \frac{1}{2}c_1a\Gamma$$

$$J = \frac{1}{2}c_1a\Gamma - \frac{1}{2}c_2a\Gamma$$

$$= \frac{1}{2}(c_1 - c_2)a\Gamma$$

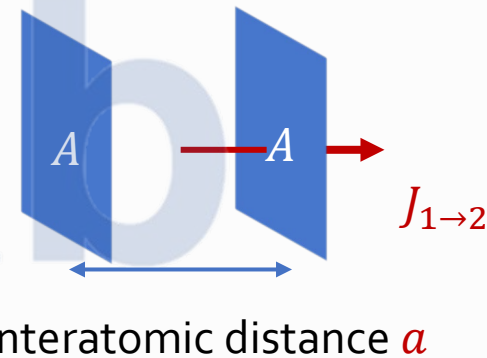
$$= -\frac{1}{2} \frac{\Delta c}{a} a^2 \Gamma$$

\downarrow
 $\frac{\partial c}{\partial x}$

Compared with $J = -D \frac{\partial c}{\partial x}$

$$D = \frac{1}{2}a^2\Gamma$$

If $c_1 = c_2 = c$, then exchange flux $J_{exch} = \frac{1}{2}ca\Gamma$



Microscopic expression of diffusivity

$$D = \frac{1}{2} a^2 \Gamma$$

Microscopic expression of diffusivity (diffusion coefficient)

Beyond 1D $\rightarrow D = \frac{1}{CN} a^2 \Gamma$

CN = coordination number, *i.e.*, the # of nearest neighbor for ion hop

$$\Gamma = \nu \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

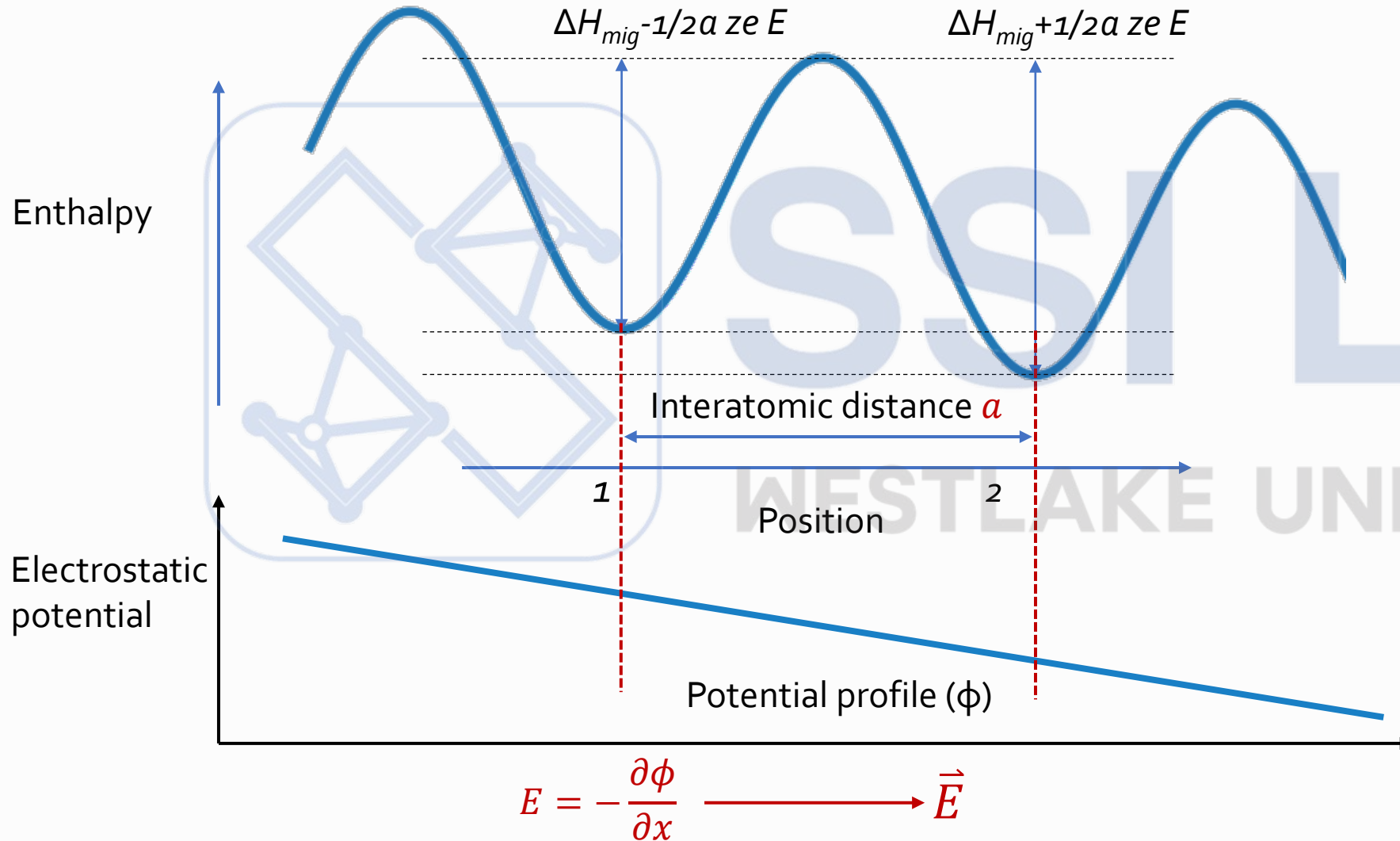
$$D = \frac{1}{CN} a^2 \nu \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

Pre-factor Thermal activation

$$D = D_0 \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

$$D_0 = \frac{1}{CN} a^2 \nu$$

Migration under an electric field



How much energy is $a z e E$ term?

- Interatomic distance $a \sim 1 \text{ nm}$
- If $\Delta\phi = 1 \text{ V}$, across a length $l = 1 \text{ mm} \rightarrow E = 10 \text{ V/cm}$

$a e E = 10^{-6} \text{ eV}$ (very small)

Compared with $k_B T = 26 \text{ meV}$ at RT

i.e., normally migration barrier is **NOT sensitive** to applied electric field.

However, if $l = 10 \text{ nm}$, then $E = 1 \text{ MV/cm}$, $a e E = 0.1 \text{ eV}$ (e.g., the case of memristors)

Migration under an electric field

Recall the *exchange flux* $J_{exch} = \frac{1}{2}ca\Gamma = \frac{1}{2}cav \exp(-\frac{\Delta H_{mig}}{k_B T})$

$$J = J_{1 \rightarrow 2} - J_{2 \rightarrow 1} = \frac{1}{2}cav \exp(-\frac{\Delta H_{mig} - 1/2 zeaE}{k_B T}) - \frac{1}{2}cav \exp(-\frac{\Delta H_{mig} + 1/2 zeaE}{k_B T})$$

Note: in this case, the concentrations at position 1&2 are the same (c), however, the migration barriers are different.

$$J = \frac{1}{2}cav \exp(-\frac{\Delta H_{mig}}{k_B T}) \left(\exp\left(\frac{1/2 zeaE}{k_B T}\right) - \exp\left(-\frac{1/2 zeaE}{k_B T}\right) \right)$$

$eaE \ll k_B T$ for low-field condition

$$\exp\left(\frac{1/2 zeaE}{k_B T}\right) \sim 1 + \frac{1/2 zeaE}{k_B T}$$

$$J = \frac{1}{2}cav \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right) \frac{zeaE}{k_B T} = \frac{1}{2}ca\Gamma \frac{zeaE}{k_B T}$$

Γ

Ion migration under an electric field

$$J = \frac{1}{2} c a \Gamma \frac{z e a E}{k_B T}$$

Recall

$$D = \frac{1}{2} a^2 \Gamma$$

$$J = c D \frac{z e E}{k_B T}$$

Since J is the flux of ions (unit: $\#/(cm^2 \cdot s)$), we need to convert to the flux of charge (unit: $C/(cm^2 \cdot s)$)

$$J_{chg} = J z e = c z e D \frac{z e E}{k_B T}$$

Plug in the expression of conductivity: $\sigma = c z e M \rightarrow$ Mobility

$$J_{chg} = \sigma \frac{D}{M} \frac{z e}{k_B T} E$$

Compared with Ohm's law: $J_{chg} = \sigma E$

We finally reach the Nernst-Einstein relation:

$$\frac{D}{M} = \frac{k_B T}{z e}$$

or if the unit is per mole:

$$\frac{D}{M} = \frac{R T}{z F}$$

Nernst-Einstein relation

The **Nernst-Einstein** relation

$$\frac{D}{M} = \frac{k_B T}{ze}$$

relates the diffusivity D and the mobility M

Recall

$$D = D_0 \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

We have: $M = \frac{ze}{k_B T} D = \frac{ze}{k_B T} D_0 \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$

$$M = \frac{A}{T} \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

$$\sigma = c ze M = cze \frac{A}{T} \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

$$\sigma = \frac{\sigma_0}{T} \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right)$$

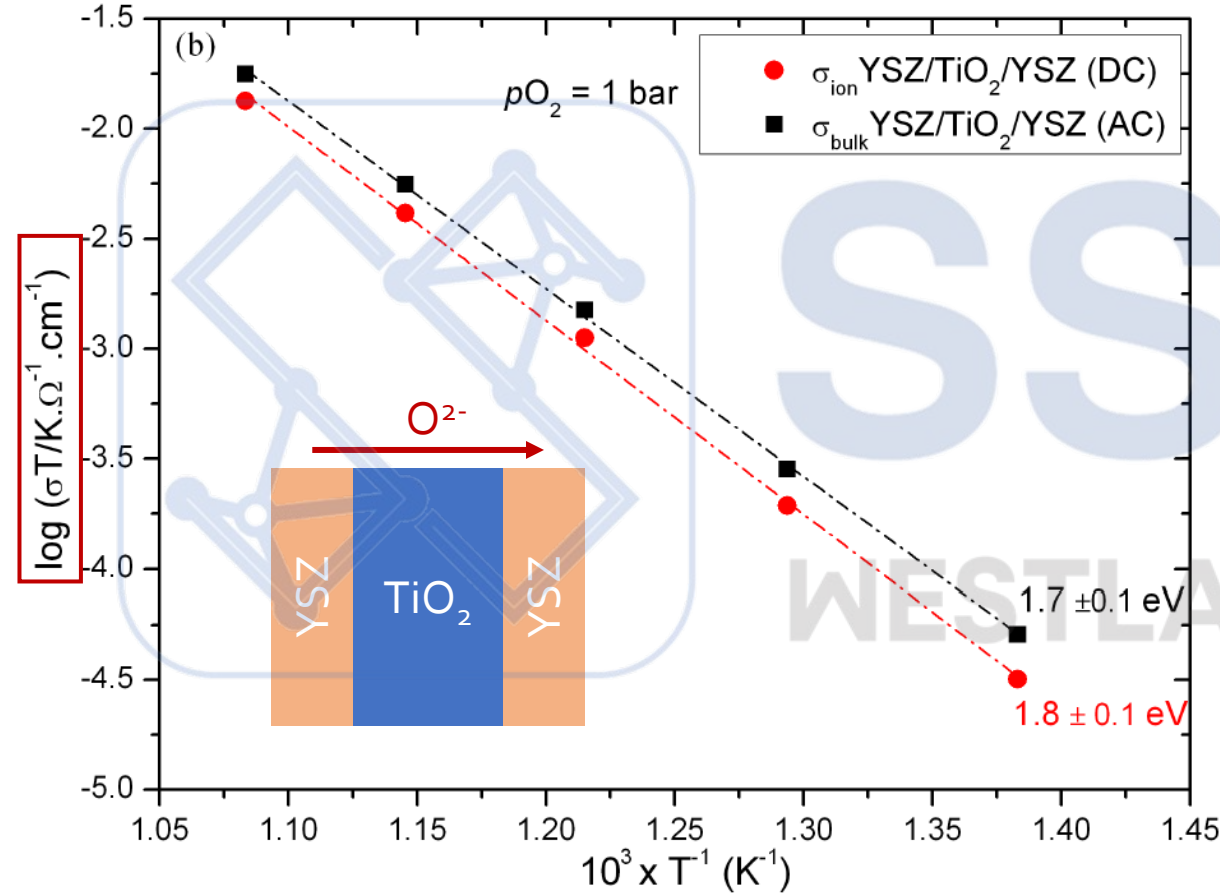
Assumption: *const. c*

Compare **mobilities** of ionic and electronic defects in SrTiO₃

Ionic (oxygen vacancy)	$\mu_V = 1.0 \times 10^4 (T^{-1}/K^{-1})$ $\times \exp\left(-\frac{0.86 \text{ eV}}{k_B T}\right) \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$
Electronic (electrons & holes)	$\mu_n = 4.5 \times 10^5 (T/K)^{-2.2} \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$ $\mu_p = 8.9 \times 10^5 (T/K)^{-2.36} \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$

Guo, Fleig & Maier, *SSI*, 2002

Temperature dependence of ionic conductivity



PhD Thesis, Kiran Adeplli, Max-Planck Institute for Solid State Research (2013)

$$\sigma = \frac{\sigma_0}{T} \exp\left(-\frac{\Delta H_{\text{mig}}}{k_B T}\right)$$

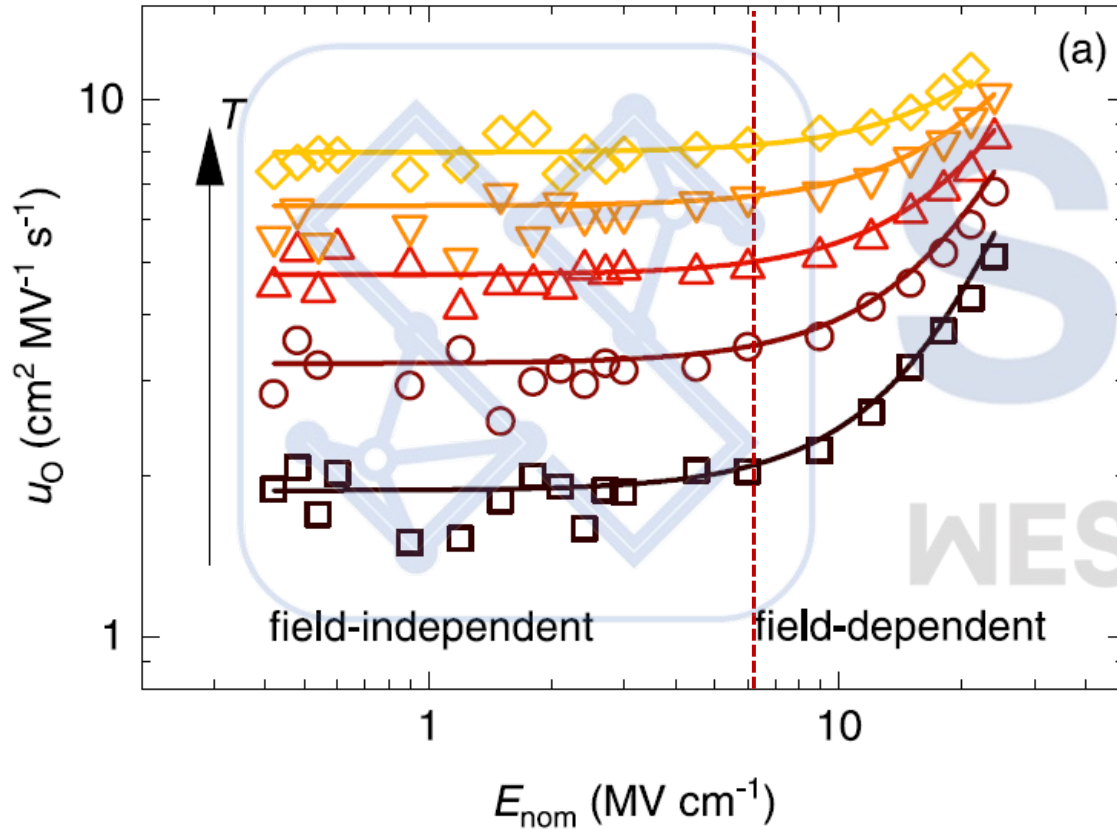
- Linear relationship of $\ln \sigma T \sim 1/T$;
- Slope $\rightarrow \Delta H_{\text{mig}}$ (again, assuming ionic defect concentration does not change).

Note:

- If the range of varying temperature is not too large, then $\ln \sigma \sim 1/T$ is almost linear.
- *Be careful what the activation energy actually mean.* If the concentration is a function of temperature, then $E_a = \Delta H_{\text{mig}} + \Delta H_f$

Formation energy

Simulated field-dependent mobility of oxide ions in SrTiO_3



Kemp & de Souza, *PRM*, 2021

Recall:

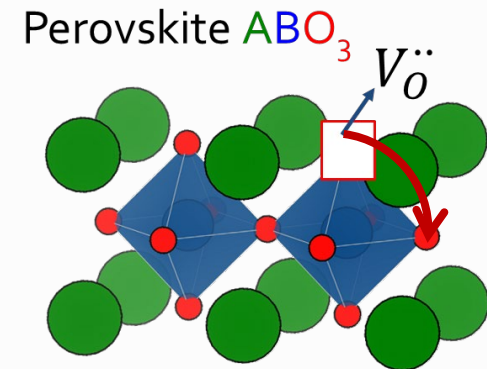
$$J = \frac{1}{2} c a v \exp\left(-\frac{\Delta H_{mig}}{k_B T}\right) \left(\exp\left(\frac{1/2 z e a E}{k_B T}\right) - \exp\left(\frac{-1/2 z e a E}{k_B T}\right) \right)$$

What if $1/2 z e a E \sim k_B T$? Then the linearization breaks down.

For SrTiO_3 , the threshold electric field is given by:

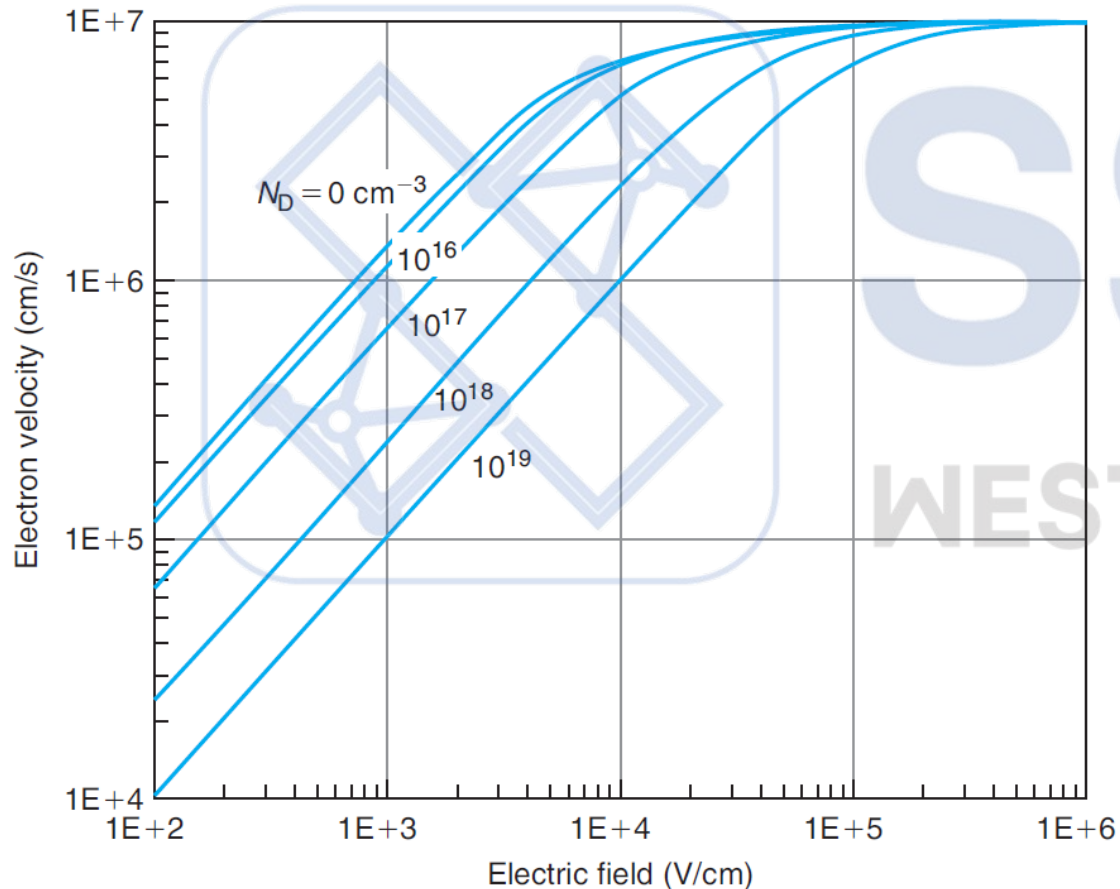
$$E_{th} = \frac{2 k_B T}{z e a} \sim 0.9 \text{ MV/cm}$$

$$(z = 2, a = \frac{\sqrt{2}}{2} d_{(100)} = 2.76 \text{ \AA})$$



Comparing the temperature dependence of mobility

For electrons in semiconductors, mobility *decreases* with increasing electric field after a threshold.



$$v = M E$$

Velocity (cm/s)

Mobility
($\text{cm}^2/(\text{V}\cdot\text{s})$)

Electric field
(V/cm)

Electronic defects

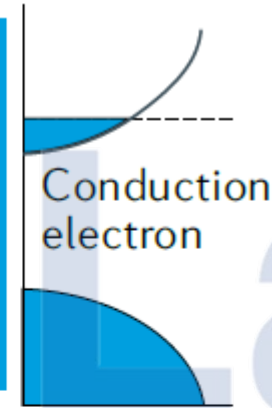
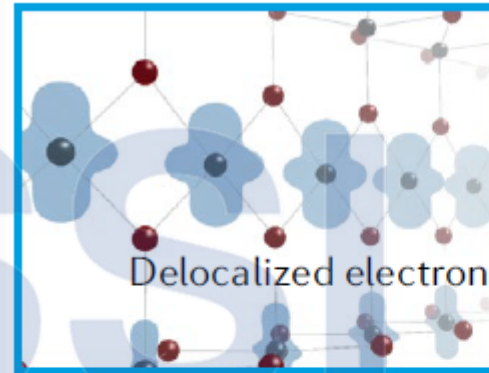
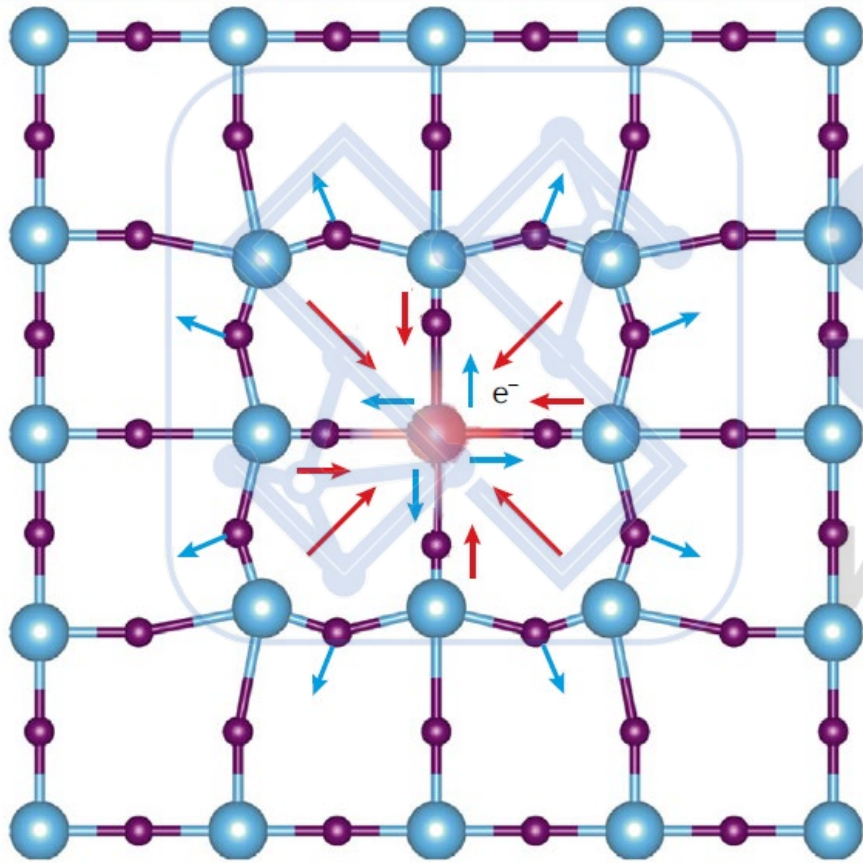
Saturation velocity \rightarrow mobility decreases linearly with electric field

Ionic defects

Energy landscape distortion \rightarrow mobility increases exponentially with electric field

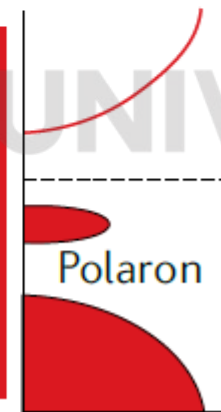
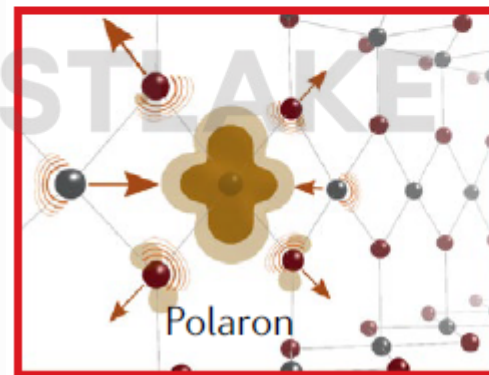
* High electric field condition (*i.e.*, above a threshold electric field)

Electron-phonon interaction \rightarrow lattice distortion



Example:

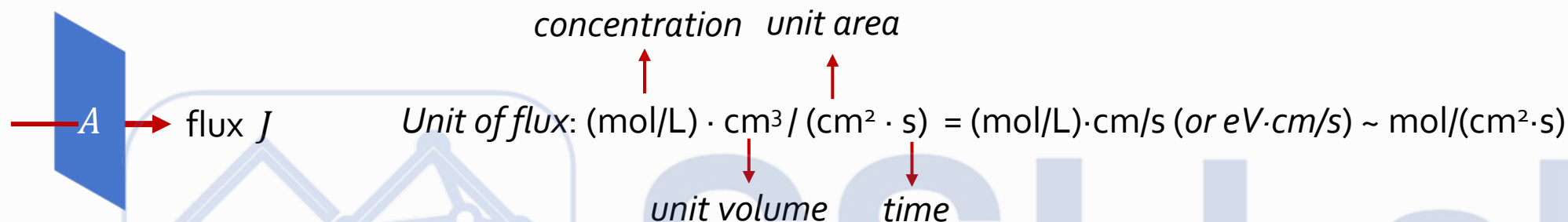
Electrons & holes in Si



Example:

Ce^{3+} (Ce'_{Ce}) in $\text{CeO}_{2-\delta}$

Polarons in many ways behave very similarly to ionic defects.
E.g., the conductivity of polarons is thermally activated.



Irreversible thermodynamics

The rate of entropy production:

$$\Pi = T \frac{\delta S}{\delta t} = \sum_k J_k X_k$$

flux

driving force

e.g., for diffusion: $\Pi = J (-\nabla \mu)$ Unit: J : $\text{mol}/(\text{cm}^2 \cdot \text{s})$; $\nabla \mu$: $(\text{J/mol})/\text{cm} \rightarrow \Pi$: $\text{J}/(\text{cm}^3 \cdot \text{s})$

At equilibrium: $\Pi = 0$ (no flow)

At "steady state": Π is minimized (constant flow) $\rightarrow \nabla \cdot J = 0$

Linear flux-force relationships

driving force
↑

flux ← $J = \beta X$

$J = D (-\nabla c)$
 $j = \sigma (-\nabla \phi)$
 $f = \lambda (-\nabla T)$

Linear flux-force relationships

Fick's Law

Ohm's Law

Fourier's Law

$J_i = -\frac{\sigma_i}{z_i^2 F^2} \nabla \tilde{\mu}_i$

→

For charged particles (ions & electrons)

* Linear relationships are valid "near-equilibrium"

Electronic current density: $j_{e^-} = -\textcolor{red}{F} J_{e^-} = \frac{\sigma_{e^-}}{F} \nabla \tilde{\mu}_{e^-}$

($z_{e^-} = -1$)

$j_{h^+} = \textcolor{red}{F} J_{h^+} = -\frac{\sigma_{h^+}}{F} \nabla \tilde{\mu}_{h^+}$

($z_{h^+} = 1$)

Onsager reciprocity: electron-ion interference

$$J_i = \underbrace{\frac{\sigma_i}{z_i^2 F^2}}_{L_i} (-\nabla \tilde{\mu}_i) \longrightarrow \text{For charged particles (ions \& electrons)}$$

L_i : connect flux with driving force;

$$\begin{array}{l} \text{flux of ionic species} \longleftarrow \\ \text{flux of electronic species} \longleftarrow \end{array} \begin{pmatrix} J_i \\ J_e \end{pmatrix} = \underbrace{\begin{pmatrix} L_{ii} & L_{ei} \\ L_{ie} & L_{ee} \end{pmatrix}}_{L_{mn}} \begin{pmatrix} -\nabla \tilde{\mu}_i \\ -\nabla \tilde{\mu}_e \end{pmatrix} \begin{array}{l} \longrightarrow \text{driving force for ionic species} \\ \longrightarrow \text{driving force for electronic species} \end{array}$$

L_{mn} : connect flux with driving force;

$$L_{ii} = \frac{\sigma_i}{z_i^2 F^2} \quad L_{ee} = \frac{\sigma_e}{F^2} : \text{Charge transport coefficient for ions and electrons}$$

$$L_{ei} = L_{ie} = ?? : \text{cross-term; "interference" effect}$$

Microscopic picture of ion transport:

- What are the microscopic mechanisms for ionic migration based on the type of ionic defects?
- How to derive the Fick's law from the microscopic picture of ion migration?
- How to reach the Nernst-Einstein relation (correlating the diffusivity and the mobility) from the microscopic picture of ion transport?

Goal of this lecture: you should be able to answer the questions above now (hopefully) :)

End of Lecture 4

Solid State Ionics Fall 2023

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